Search Notes

Application/Control No.	Applicant(s)/Patent und r R xamination
09/683,432	BENAYOUN ET AL.
Examin r	Art Unit
Dmitry Levitan	2616

SEARCHED						
Class	Subclass	Date	Examiner			
370	357 360		オム			
	369 - 389					
			/			
	395.1	75/31/	06			
	395.3					
	396					
	400					
	396 400 401					

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)					
	DATE	EXMR			
IEEE, EAST	5/31/06	De			